Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/751,834	CHEN, WEN CHOU	
Examiner	Art Unit	
KEVIN L. LEE	3753	

	SEARCHED				
Class	Subclass	Date	Examiner		
137	66 613 65 883	5/3/2006	KL		

INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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